

Impact of Raman scattering on XCO₂ and SIF retrievals from OCO-2/3

Suniti Sanghavi¹, **Christian Frankenberg**^{1,2},
Robert Nelson¹, Christopher O'Dell³, Robert Rosenberg¹, Joanna Joiner⁴
1 NASA Jet Propulsion Laboratory, 2 California Institute of Technology, 3 Colorado State University, 4 NASA Goddard Space
Flight Center

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IWGGMS, Takamatsu, Japan

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Background

- Ever since its first detection from space, SIF retrievals have required posterior bias corrections using barren reference areas like the Sahara, Antarctica, and Greenland – these biases were assumed attributable to instrument artefacts encapsulated as the “zero level offset” (ZLO)
- Recent advances in radiative transfer modeling have revealed that these biases may be explained by rotational Raman scattering (RRS)
- The resulting simulations could explain part of the original biases in SIF, as well as residual biases that remained after ZLO corrections
- We have generated a lookup table (LuT) to correct for RRS biases in SIF and XCO₂ retrievals from OCO-2 and other instruments

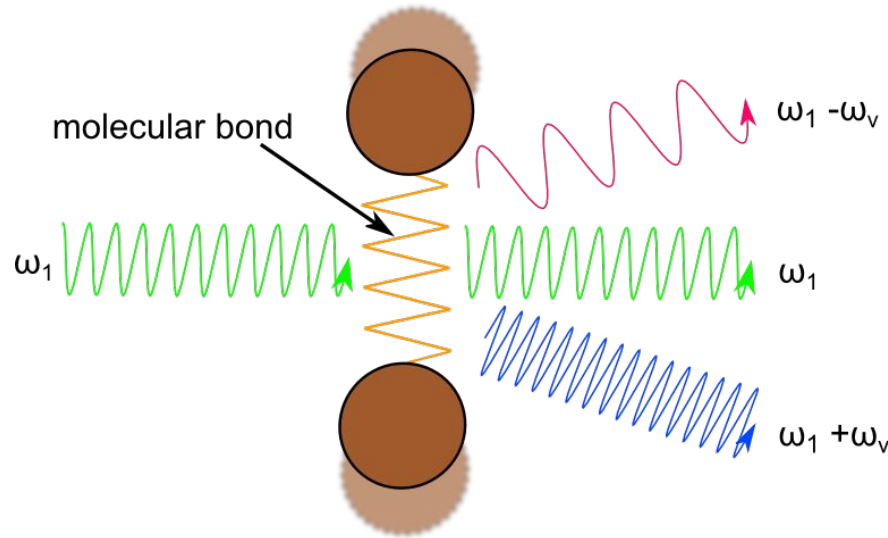
Raman Scattering Basics



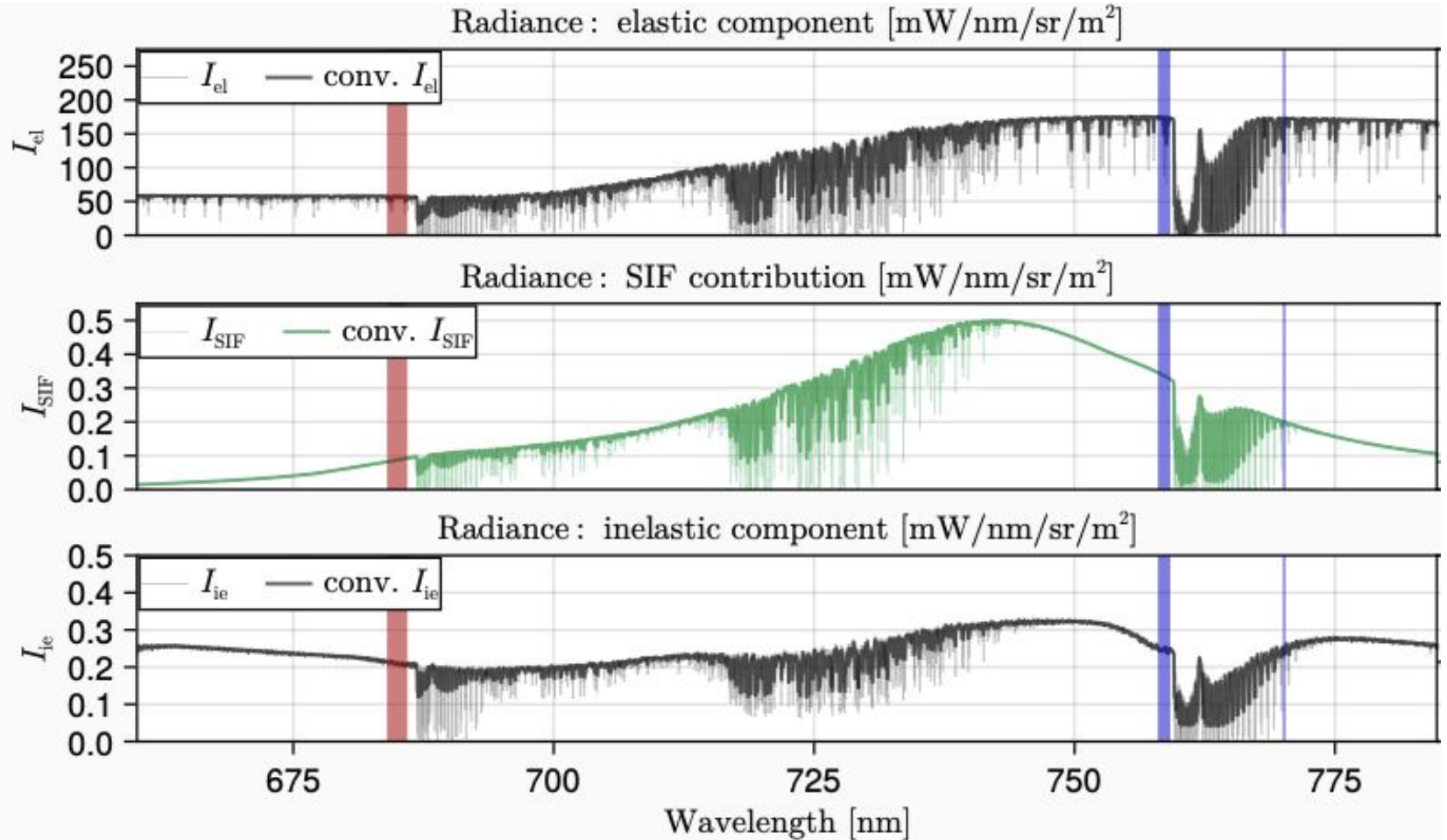
Sanghavi, Raman scattering in the earth's atmosphere, part I: Optical properties, JQSRT 2022



Sanghavi and Frankenberg, Raman scattering in the Earth's atmosphere, Part II: Radiative transfer modeling for remote sensing applications, JQSRT 2023

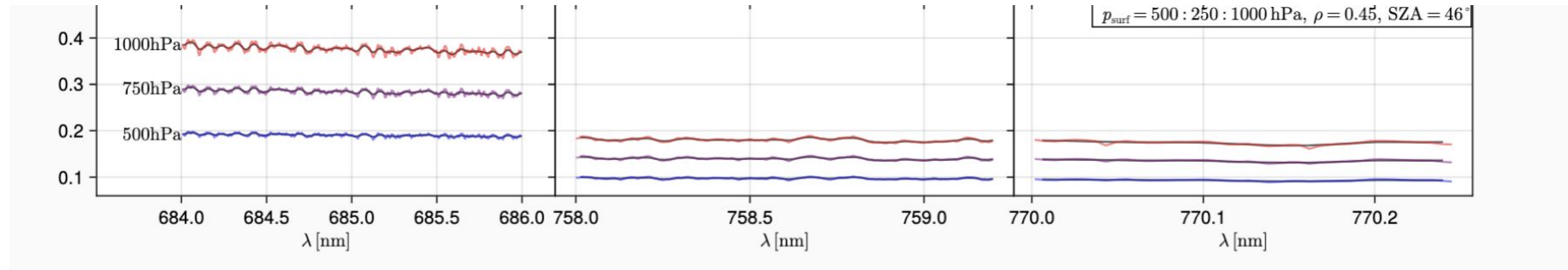


How does RRS affect SIF retrievals?



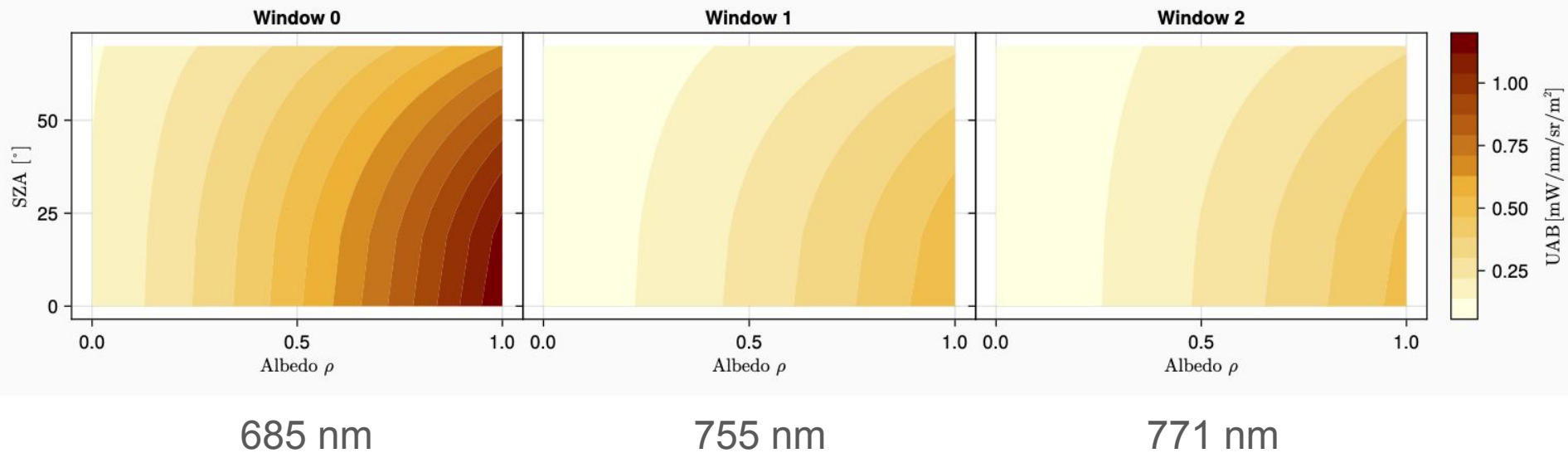
How does RRS affect SIF retrievals?

Surface Pressure (mostly topography)

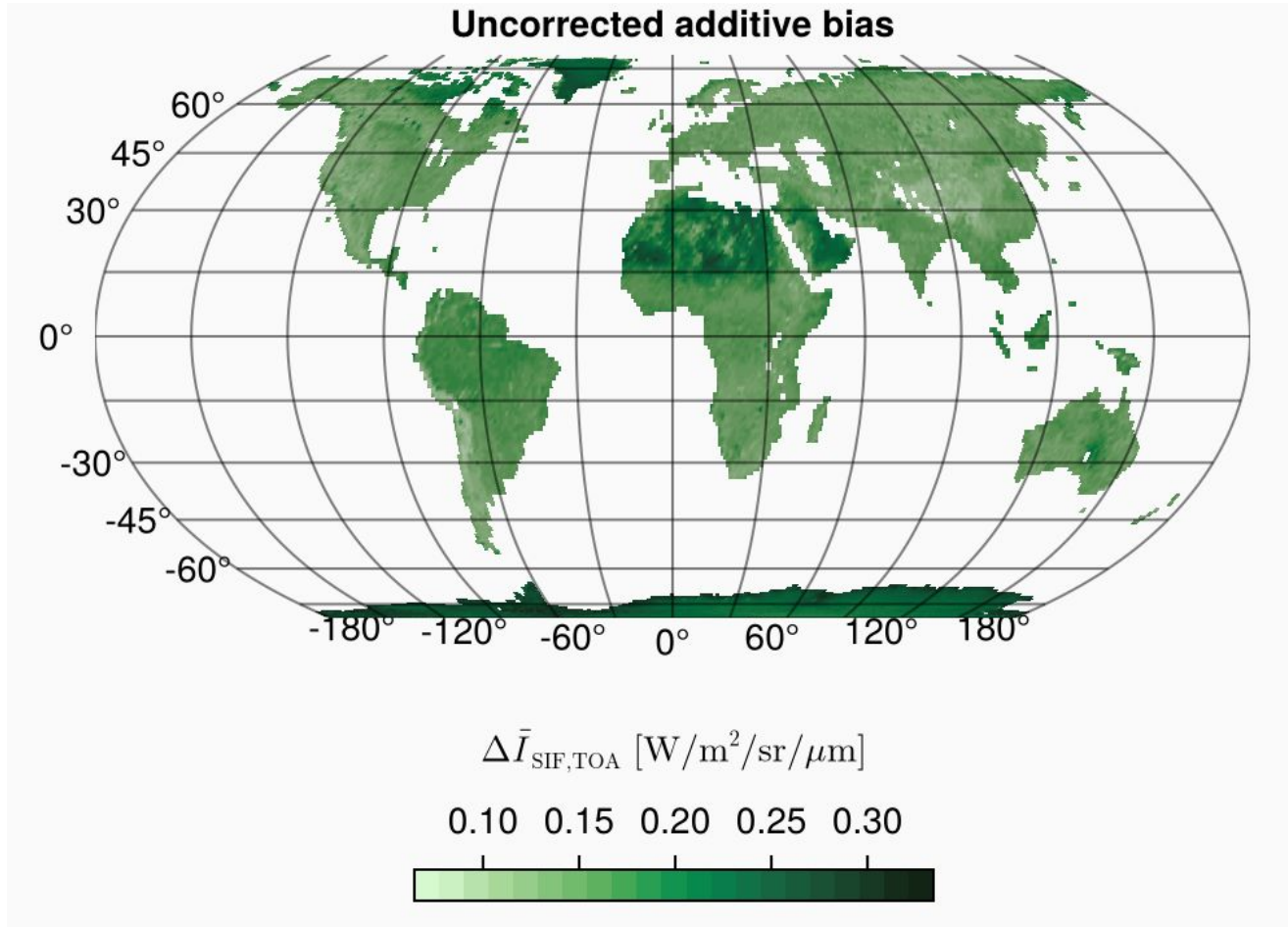


How does RRS affect SIF retrievals?

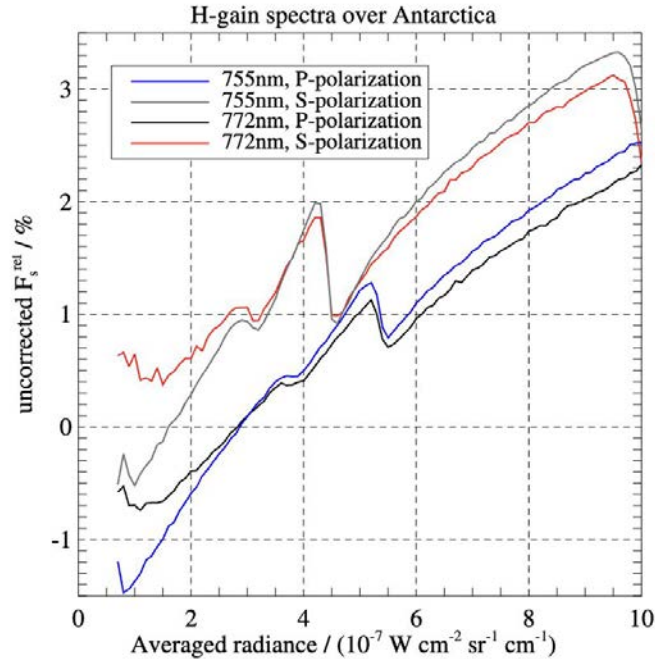
(b) Retrieval bias



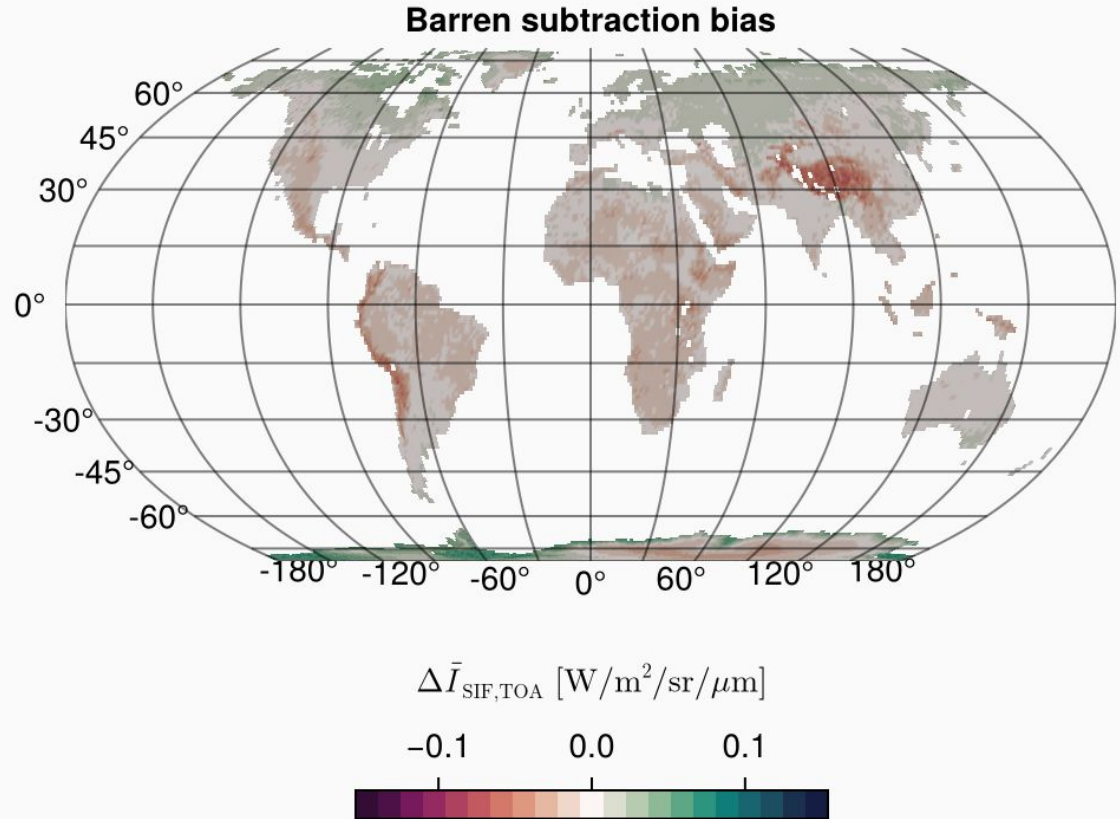
Uncorrected SIF: Simulated biases



ZLO corrected SIF: GOSAT observations, simulated biases

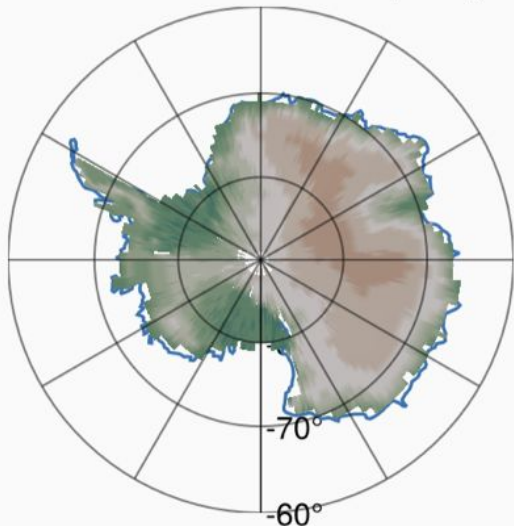


Frankenberg et al. 2013

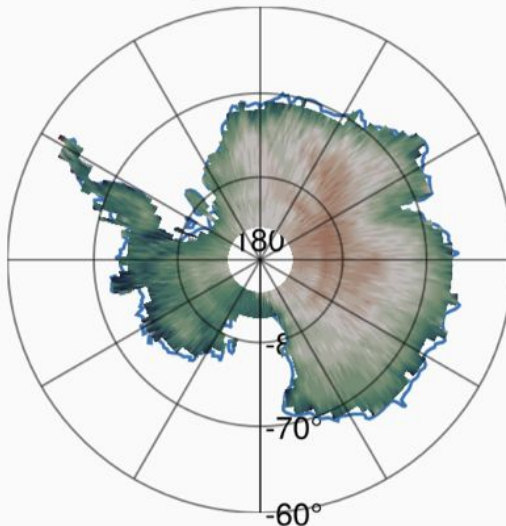


ZLO corrected SIF: simulated biases, OCO-2/TROPOMI observations

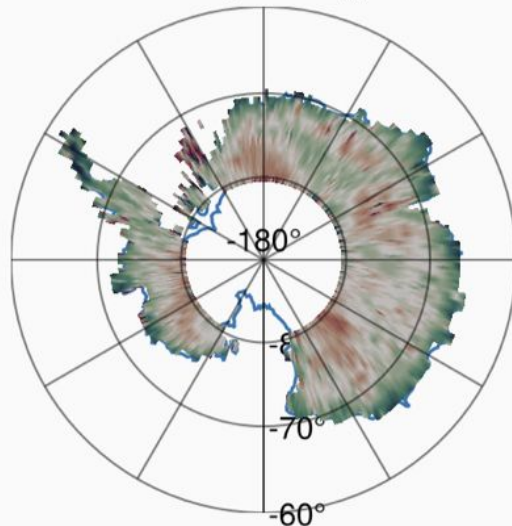
Bias after std. OCO-2 correction (BSB), modeled



OCO SIF (757 nm), observed



TROPOMI SIF (757 nm), observed



$\bar{I}_{\text{SIF,TOA}}$ [$\text{W}/\text{m}^2/\text{sr}/\mu\text{m}$]

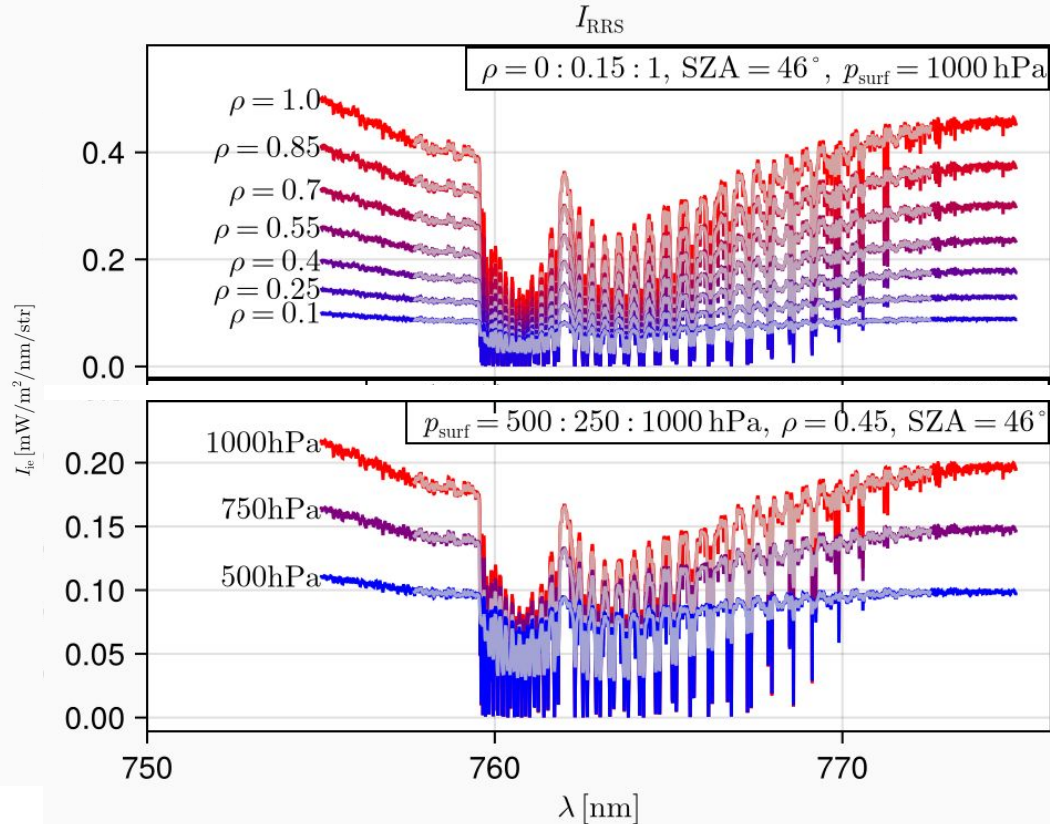
-0.1

0.0

0.1

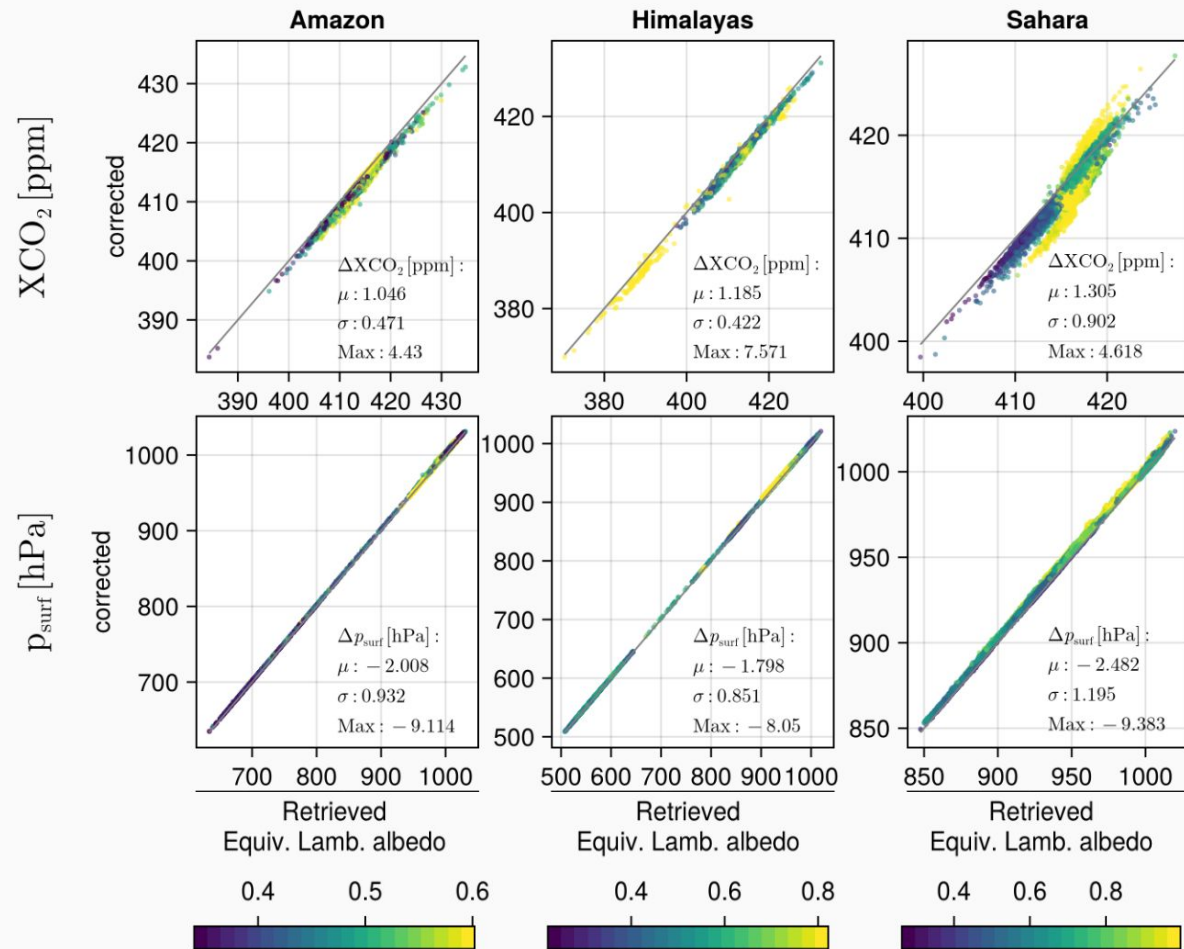


Effect of RRS on XCO₂ using the O₂ A-band: first results



Sanghavi et al. (in prep.)

Effect of RRS on XCO₂ using the O2 A-band: first results (with vs without RRS correction)



NOT negligible if
we require
<0.5-1ppm biases

Sanghavi et
al. (in prep.)

Summary and outlook

- RRS causes infilling in Fraunhofer lines and the O₂ A-band causing biases in SIF (simple and linear) and $p_{\text{surf}}/\text{XCO}_2$ retrievals (complex and non-linear).
- RRS biases depend on surface brightness, pressure, and viewing geometry, reaching ± 0.15 mW/nm/sr/m² (for ZLO-corrected SIF) and a few ppm for XCO₂
- RRS corrections to be incorporated in build 12 (B12) of the OCO-2/3 operational products (now pending NASA budgetary decisions)